

Title: TEST BOARD EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS
 ACCURACY ON AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS

Inventors: Giuseppe Di Gregorio et al. Express Mail No.: EL755716868US Docket No.: 856063.678

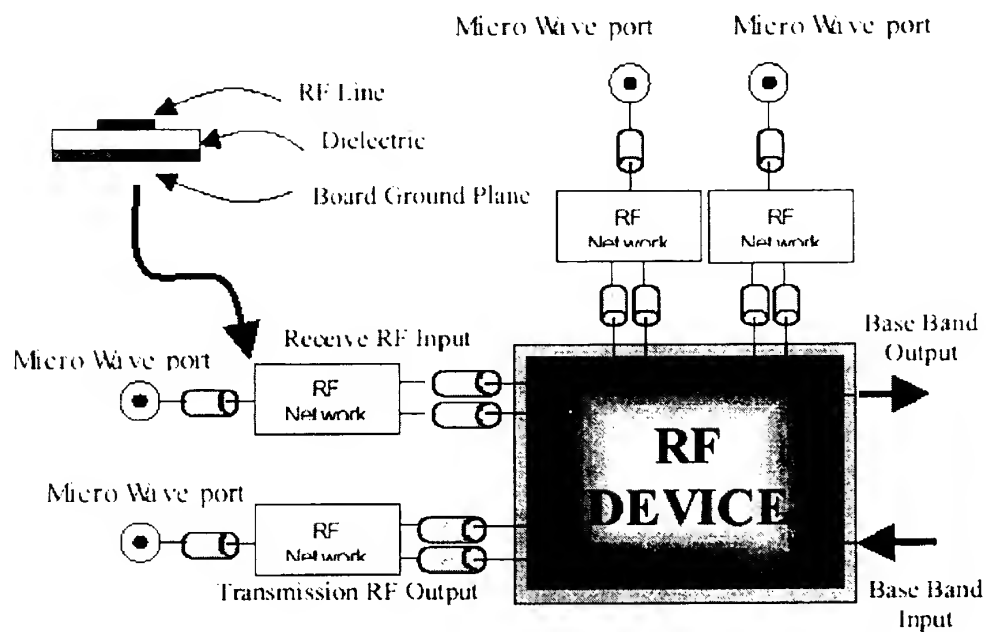


FIG. 1

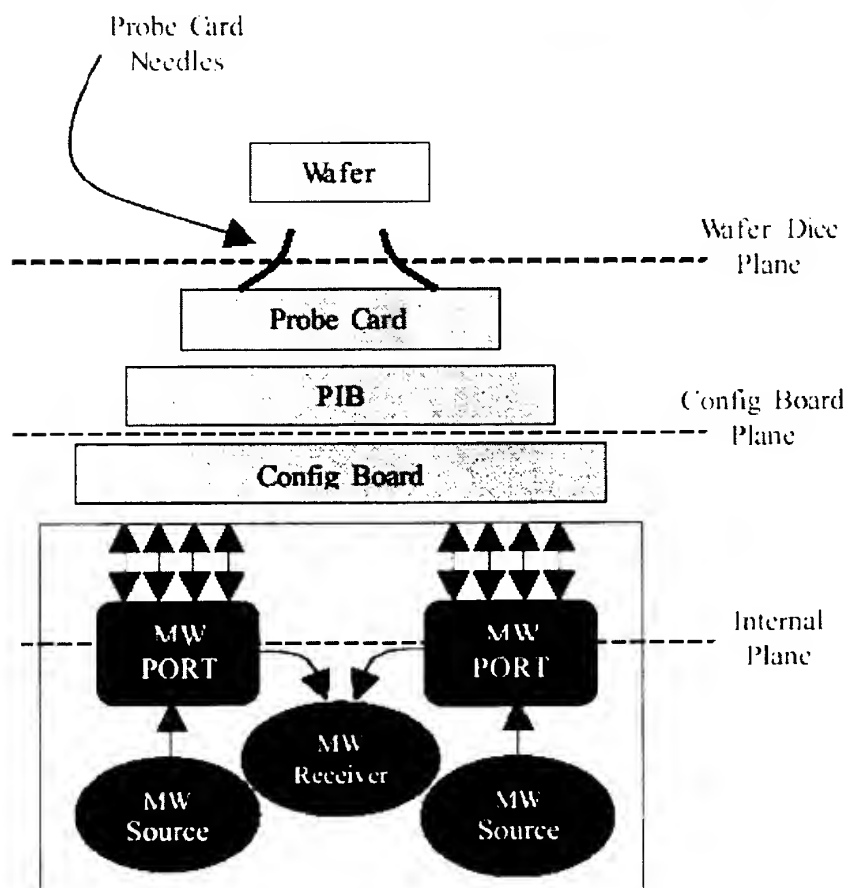


FIG. 2

Title: TEST BOARD CO-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS
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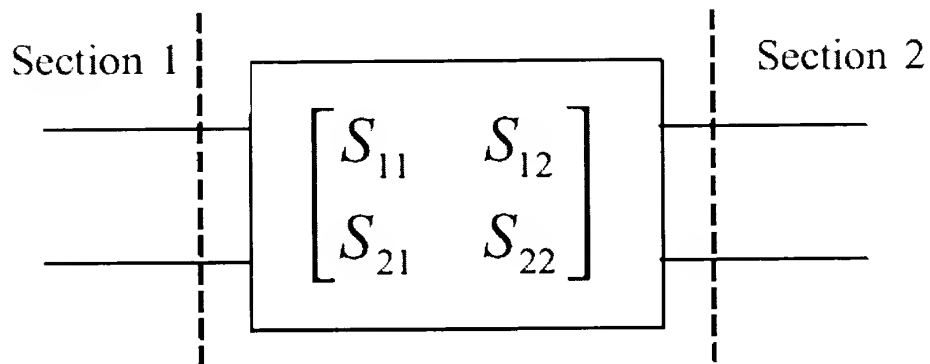


FIG. 3

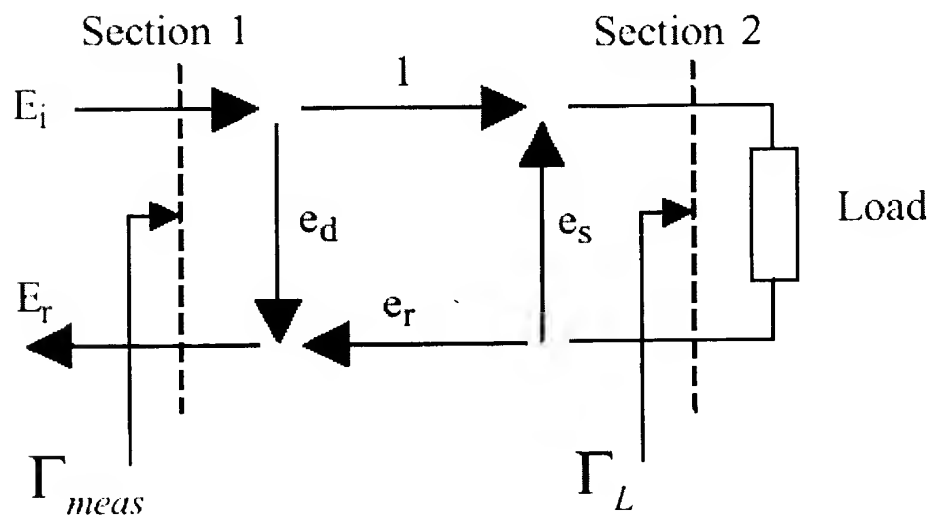


FIG. 4

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS
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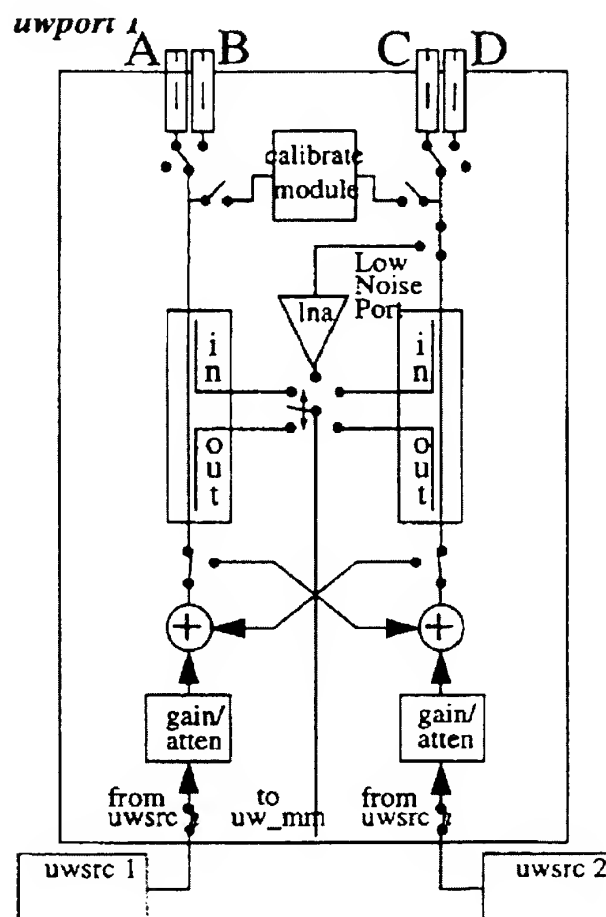


FIG. 5

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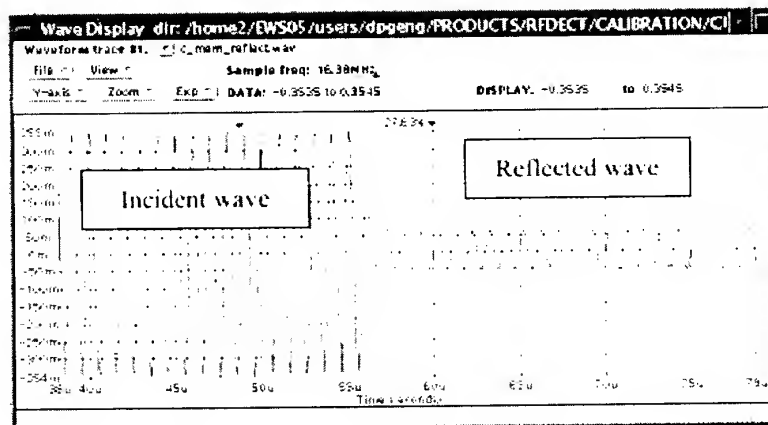


FIG. 6

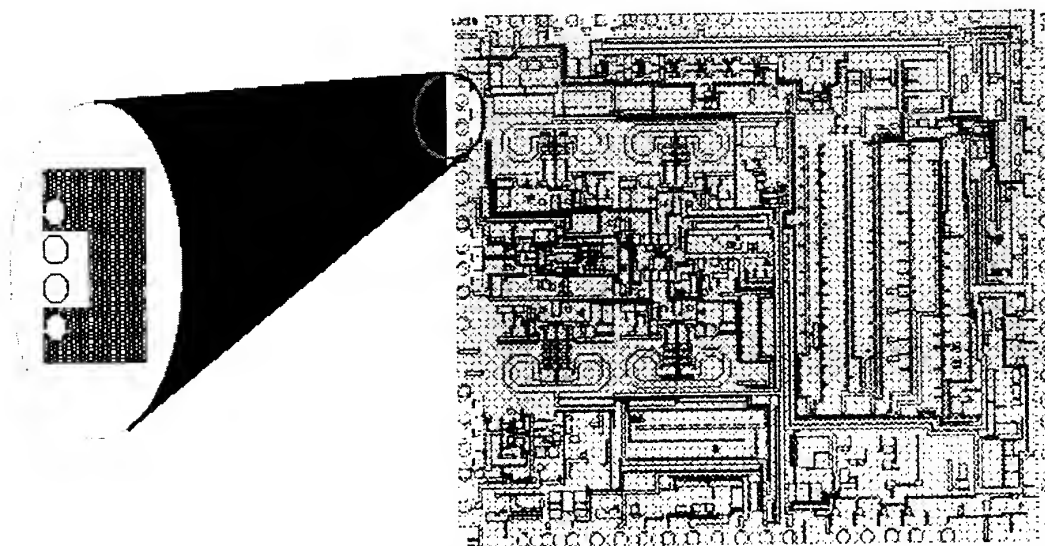


FIG. 7

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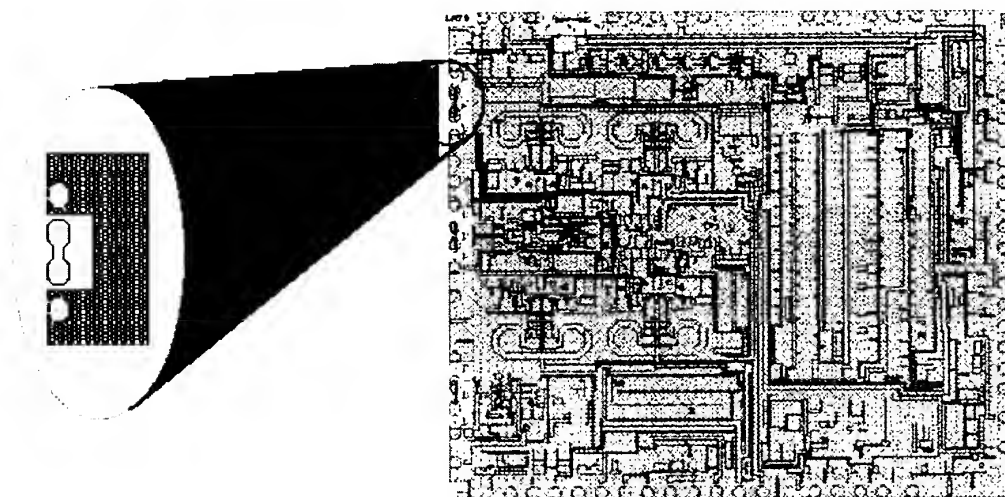


FIG. 8

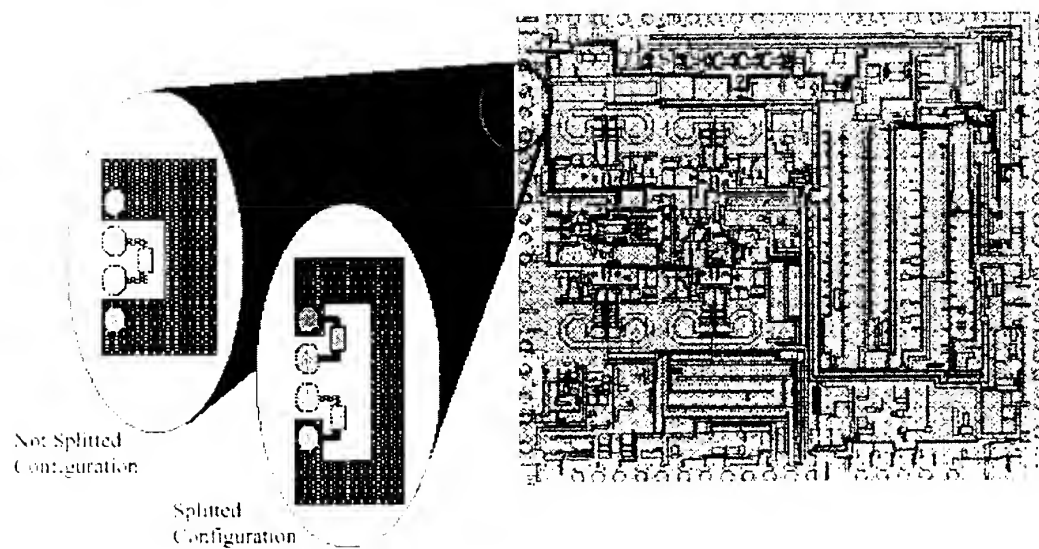


FIG. 9

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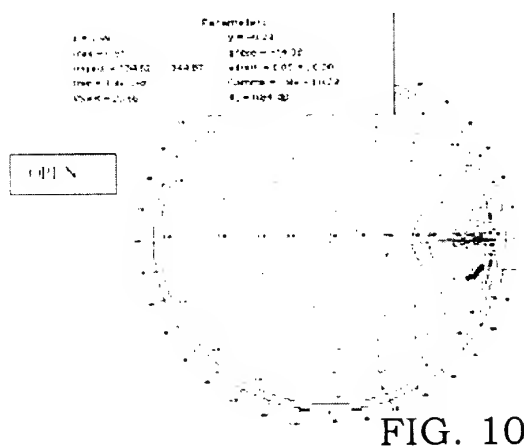


FIG. 10

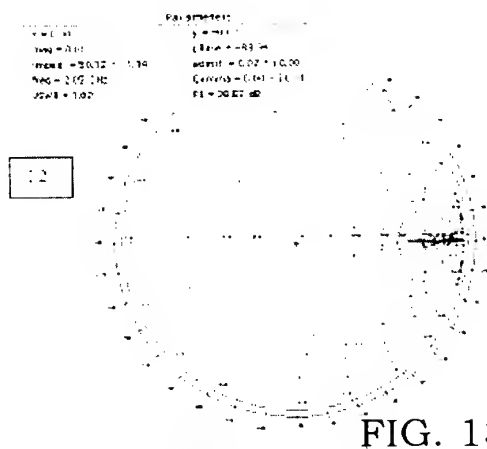


FIG. 13

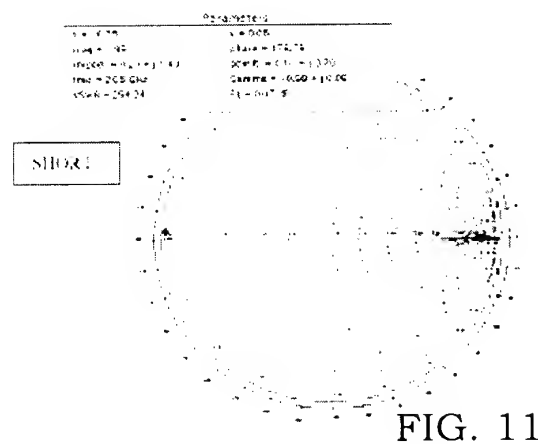


FIG. 11

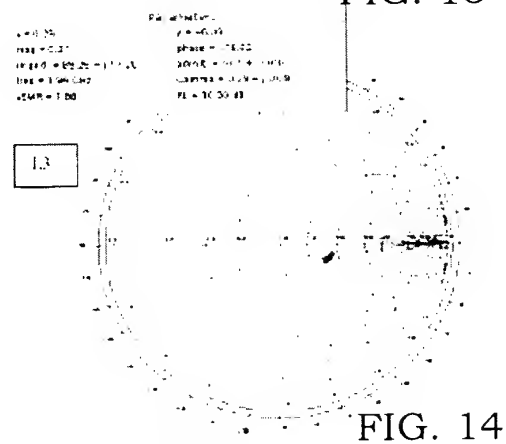


FIG. 14

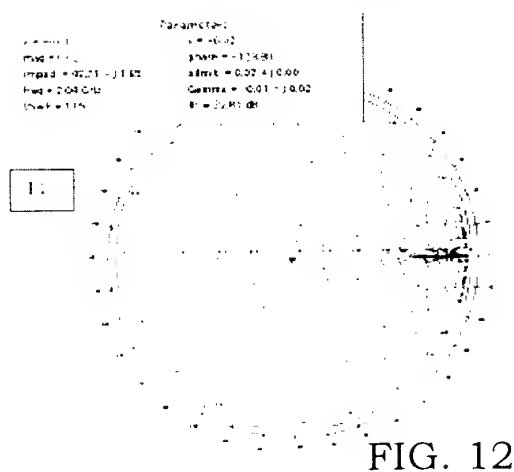


FIG. 12

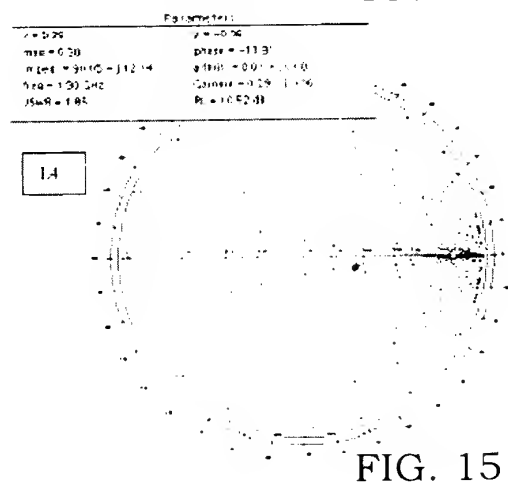


FIG. 15

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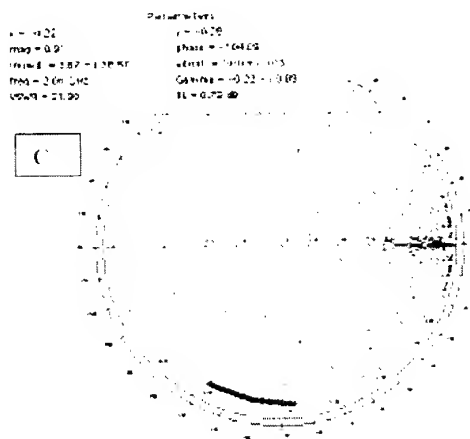


FIG. 16

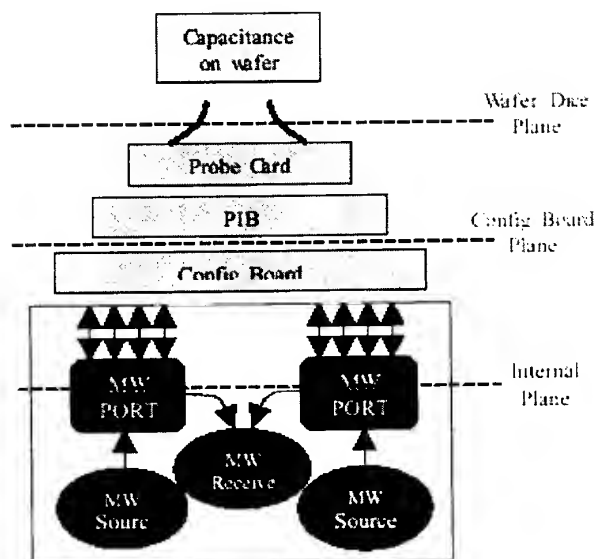


FIG. 17

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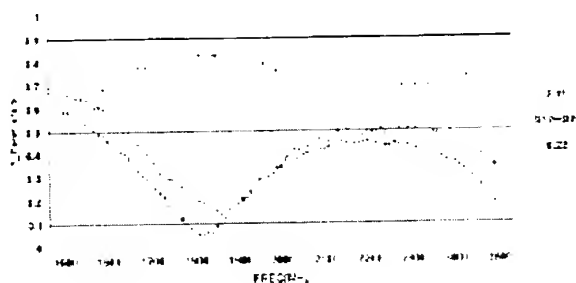


FIG. 18

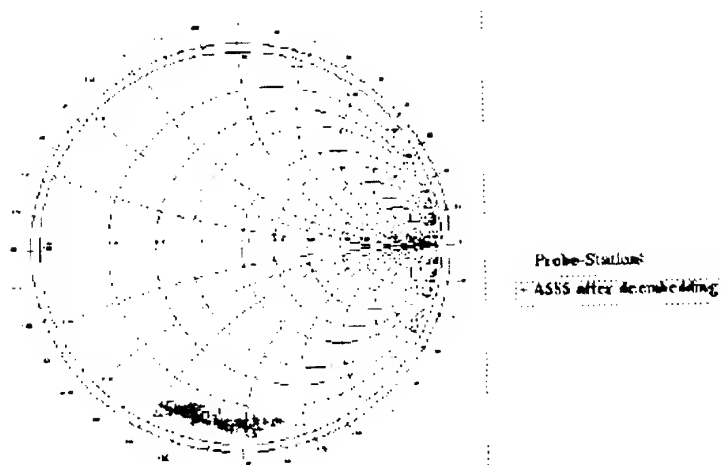


FIG. 19

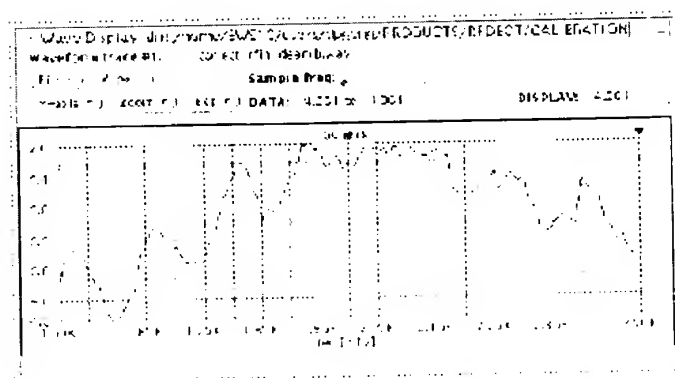


FIG. 20

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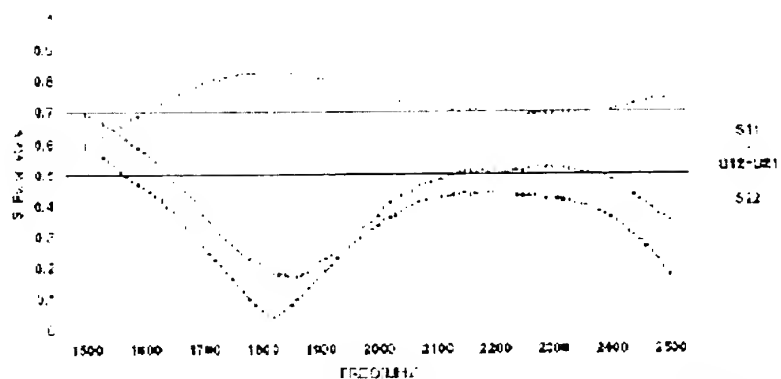


FIG. 21

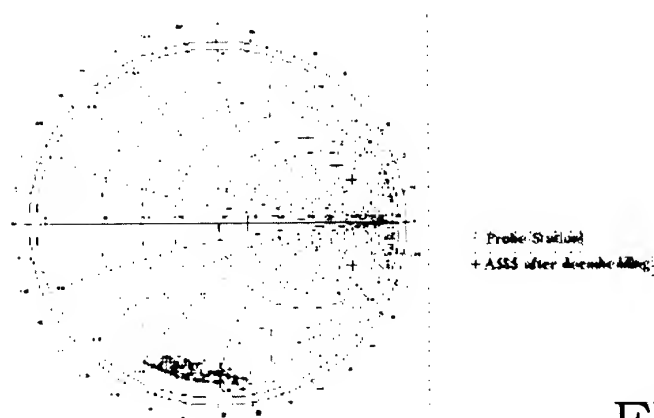


FIG. 22

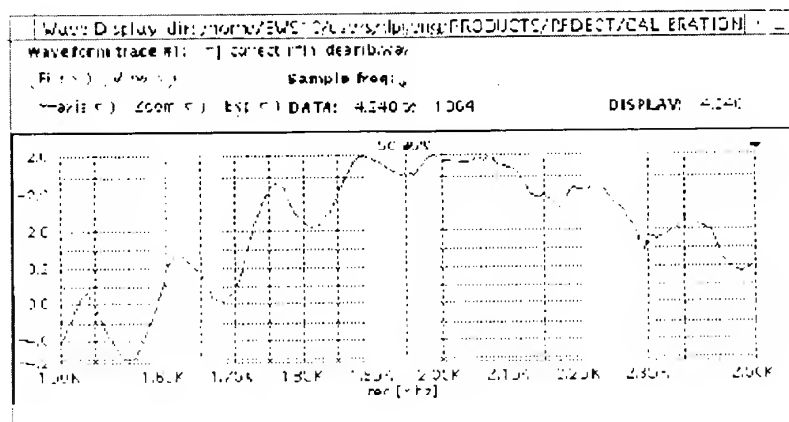


FIG. 23

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS
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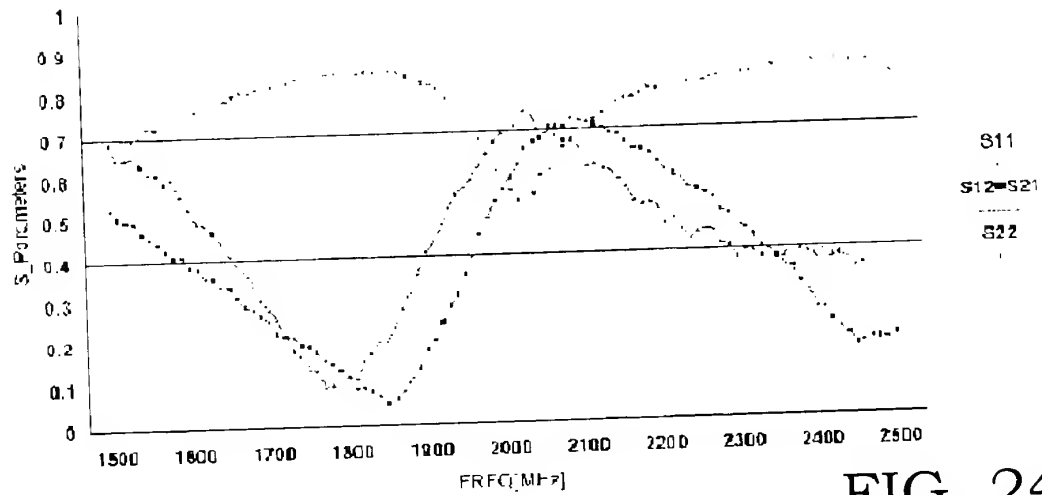


FIG. 24

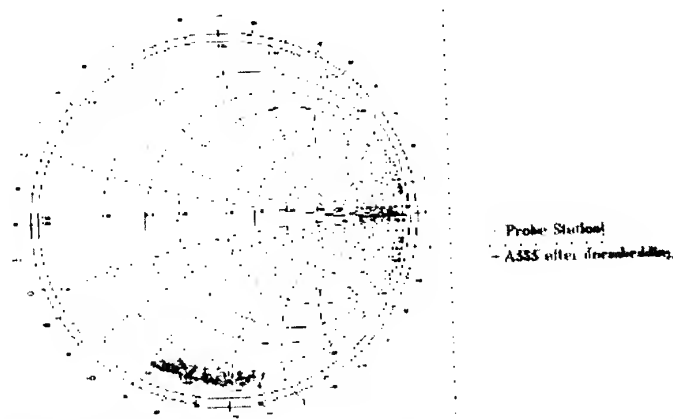


FIG. 25

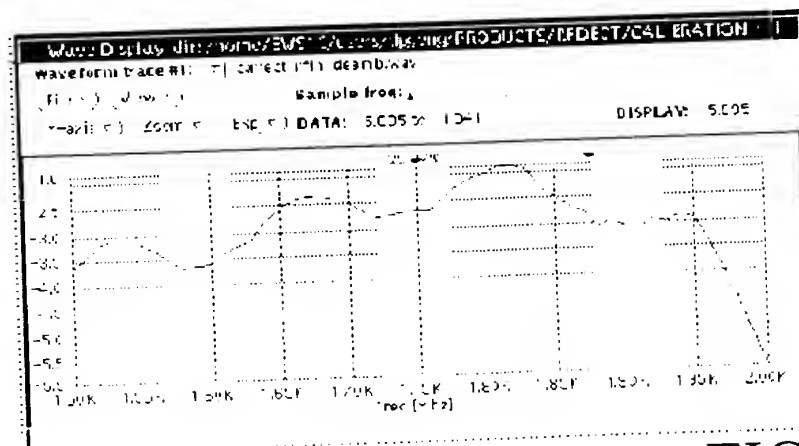


FIG. 26

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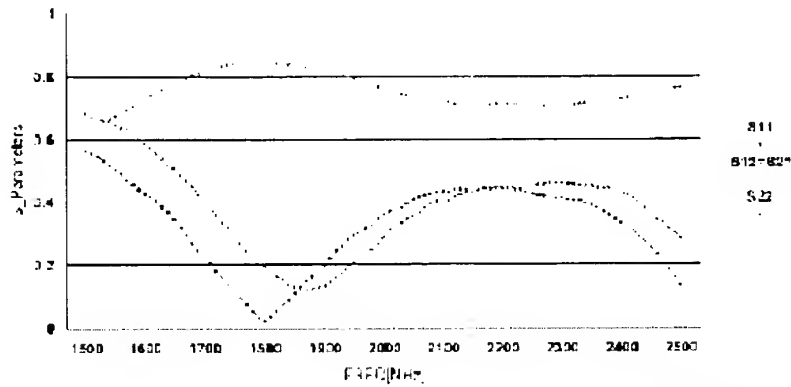


FIG. 27

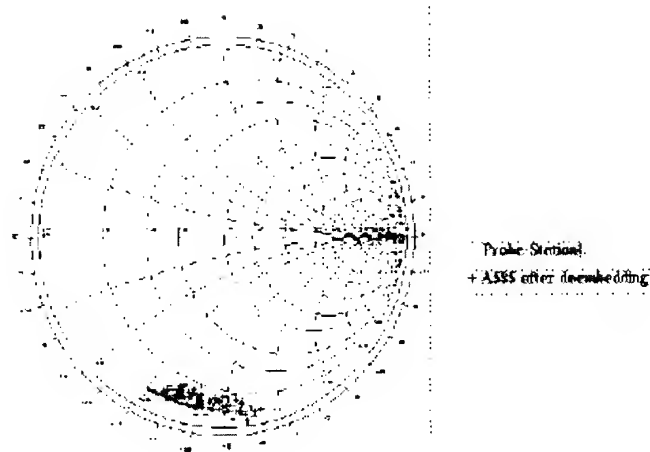


FIG. 28

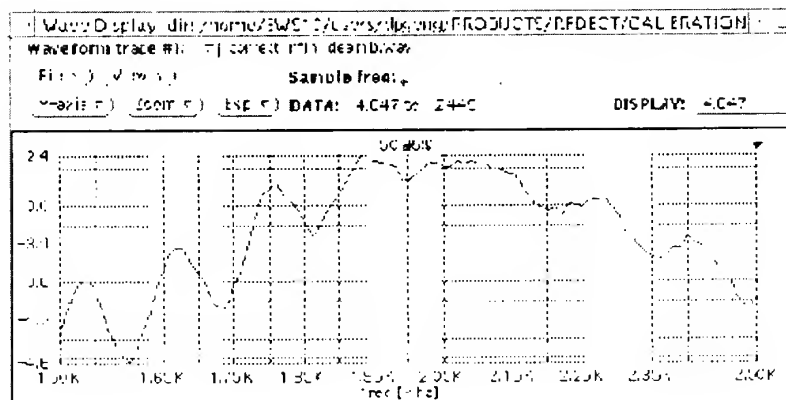


FIG. 29